GSM-20H10

Precision DC Source Meter



CE	RS-232	USB Host	USB Device	LAN
Digit I/O	GPIB			



GW Instek GSM-20H10 is a precision source meter that provides highly stable DC power and instrumentgrade 6½-digit multimeter measurements. While operating, it can be used as a voltage source, current source, voltmeter, ammeter, and ohmmeter, which is uniquely ideal for the evaluation of component characteristics and the test applications of production, including nanomaterials and components, semiconductor architecture, organic materials, high-efficiency illumination, passive components and material characteristics analysis, etc.

GSM-20H10 provides four-quadrant operation of $\pm 210V/\pm 1.05A/22W$. The first and third quadrants operate as power supplies to supply power to the load. The second and fourth quadrants function as loads to consume power internally. Voltage value, current value and resistance value can be measured while operating the power supply or load function with an accuracy of 0.012% and a resolution of 1μV/10pA/10μΩ.

With respect to sampling rate, GSM-20H10 supports a sampling rate of up to 50k points/second, which can accurately analyze the characteristics of the DUT. With the large 4.3-inch screen, all measurement settings, parameters and results can be completely displayed on the screen. The SDM (Source Delay Measure) function is provided to delay sampling when the signal changes so as to prevent the unstable signal from being captured and cause misjudgment. There are four built-in sequence output modes (Stair, Log, SRC-MEM, Custom), which can support up to 2500 points of sequence variation output.

Pertaining to protection, GSM-20H10 provides OVP/OTP modes. The design of OVP allows users to self-define the range of OVP. OTP can effectively prevent errors caused by temperature drift during the test process. For interfaces, this product supports standard SCPI commands and provides RS-232, USBTMC, LAN, GPIB (optional) interfaces to meet users' different interface needs

SPECIFICATIONS NOTE :

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 1. Speed = Normal (1) NPLC). For 0.1 PLC, add 0.005% of range to offset specifications, except 200mV, 1A ranges, add 0.5%.
 2. Required to reach 0.1% of final value after Command is processed. Resistive load. 10µA to 100mA range.
 2. Neershoot into a fully resistive 100k2 load, 10Hz to 1MHz BW, adjacent ranges : 100mV typical, except 20V/200V.
 4. Maximum time required for the output to begin to change following the receipt of : SOURce : VOLTage[CURRent <nrf. Command.
 8. Reading rates applicable for voltage or current measurements, autorange off, filter off, display off, trigger delay = 0, and binary reading forma.
 6. Purely resistive lead. 1µA and 10µA ranges <65ms.
 7. 1000 point sweep was characterized with the source on a fixed rang.
 8. Pass/Fail test performed using one high limit and one low math limit.
 9. Includes time to re-program source to a new level before making measurement.

- 9. Includes time to re-program source to a new level before making measurement. 10. Time from falling edge of START OF TEST signal to falling edge of END OF TEST signal. 11. Command processing time of : SOURce : VOLTage(CURRent : TRICgreed https://www.command.com 11. Command processing time of : SOURce : VOLTage(CURRent : TRICgreed https://www.command.com
- and not included.





FEATURES

- * Maximum Output ±210V/±1.05A/22W
- * Built-in 4 Sequence Output Modes (Stair, Log, SRC-MEM, Custom), up to 2500 Points
- * OVP /OTP Protection Function
- * 0.012% Basic Measure Accuracy with 61/2-digit Resolution
- * Variable Sampling Speed
- * SDM (Source Delay Measure) Cycle
- * 2-, 4-, and 6-wire Remote V-source and Measure Sensing
- * Variable Display Digits
- * Built-in Limit Function
- * Built-in 5 Calculation Functions
- * 4.3" TFT LCD, Digital Number Keyboard
- * Built-in RTC Clock
- * Interface: RS-232, USBTMC, LAN, GPIB (Optional)

APPLICATIONS

- * Semiconductor Component Characteristic Testing
- * Energy and Efficiency Characteristic Testing
- * Organic Material Characteristic Testing
- * Nanomaterial Characteristic Testing

	Voltage		±210V									
IAXIMUM	Current Power Voltage Resolution		±1.05A 22W 1μV									
ANGE												
	Current Resolution	Output Voltage	10pA +21V/+1.05A +	210V / +105 m4								
		Current Limit	±21V / ±1.05A, ±210V / ±105 mA Min. 0.1% of range									
		Programming Resolution &	Range Resolution		.000mV μV	±	2.00000V 10μV		±20.0000V 100μV			±200.000V 1mV
SOURCE		Accuracy *1	Accuracy		μν 6+600μV)	±(0.0	02%+600µV)		±(0.02%+2.4m)	V)	±(0.02%+24mV)
	DC Voltage	Load Regulation Line Regulation	0.01% of range + 0.01% of range	100µV								
		Overshoot		l scale step,resistive lo	ad, 10mA range)							
		Recovery Time (1000% Load Change)	<250µs (within 0.1% plus load regulation errors, 1A and 100mA compliance.)									
		Ripple and Noise	4mVrms(20Hz~1MHz) / 10mVpp(20Hz~1MHz)									
		Temperature Coefficient Output Current	±(0.15 × accuracy specification)/°C (0°-18°C & 28°-50°C) ±1.05A / ±21V, ±105 mA / ±210V									
		Voltage Limit	Min. 0.1% of ran	ge ±1.00000μA	±10.0000µA	. 100	.000μΑ	±1.00000mA	±10.00000	h A	±100.000mA	±1.00000A
		Programmed Source Resolution & Accuracy *1	Range Resolution	±1.00000μA 10pA	100pA	1	InA	±1.00000mA 10nA	±10.00000 100nA		±100.000mA 1μA	±1.00000A 10μA
	DC Current	Load Regulation	Accuracy 0.01% of range +	±(0.035%+600pA)	±(0.033%+2nA) ±(0.031	%+20nA)	±(0.034%+200nA)	±(0.045%+	2μA) ±	:(0.066%+20µA)	±(0.27%+900µ4
		Line Regulation	0.01% of range	•								
		Overshoot Temperature Coefficient		$hA \text{ step}, RL = 10k\Omega, 20$ specification)/°C (0°-								
		Output Settling Time *2	100µs typical tim	e								
		Output Rise Time (±30%) DC Floating Voltage	300µs, 200V range, 100mA compliance ; 150µs, 20V range, 100mA compliance Output can be floated up to ±250VDC Up to 1V drop per load lead									
	General	Remote Sense										
		Compliance Accuracy Range Change Overshoot *3			ng to base specification V, 2V and 20V ranges, 10	0mV typical						
		Minimum Compliance Value	Adjacent range changes between 200mV, 2V and 20V ranges, 100mV typical 0.1% of range									
		Command Processing Time *4 Input Resistance	Autorange On:10 >10 GΩ	ms. Autorange Off: 7n								
	Voltage	Measurement Resolution &	Range Resolution		000mV	±	2.00000V 10μV		±20.0000V 100μV			±200.000V 1mV
	Tonage	Accuracy	Accuracy	±(0.012	μV %+300μV)	±(0.0	10μν 012%+300μV)		±(0.015%+1.5m	iV)	±(0.015%+10mV)
		Temperature Coefficient Voltage Burden (4-wire mode)	±(0.15 × accurac) < 1mV	specification)/°C (0°-	~18°C & 28°~50°C)							
		Programmed Source Resolution &	Range	±1.00000µA	±10.0000µA		.000μΑ	±1.00000mA	±10.00000	ImA	±100.000mA	±1.00000A
	Current	Accuracy *1	Resolution Accuracy	10pA ±(0.029%+300pA	100pA ±(0.027%+700p)		1nA 5%+6nA)	10nA ±(0.027%+60nA)	100nA ±(0.035%+6	00nA) :	1μΑ ±(0.055%+6μΑ)	10μA ±(0.22%+570μ
MEASUREMENT		Temperature Coefficient		specification) / °C (0°	~18°C & 28°~50°C)					<i>.</i>		
			Resolution	<2.00000Ω	2.000 10µ		20.0000 100μΩ		200.000Ω 1mΩ		000kΩ 0mΩ	20.0000kΩ 100mΩ
	г	1	Test current				100mA		10mA	1	mA	100µA
		D	Accuracy	Source IACC+Meas	.VACC Source IACC+		±(0.1%+0.003Ω) 0.07%+0.001Ω)		+0.03Ω), Normal 0.01 Ω), Enhanced		.3Ω), Normal 1Ω), Enhanced	±(0.06%+3Ω), Norn ±(0.04%+1Ω), Enhan
		Range	200.000kΩ 2.00000MΩ 20.0000MΩ 200.000MΩ >200.000MΩ									
			Decelution					10 2		-		
	Resistance		Resolution Test current	1Ω 10μΑ	10 5µ	Ω Α	20.0000M 100Ω 0.5μA	2	00.000ΜΩ 1kΩ 100nA			
	Resistance			1Ω 10μΑ ±(0.07%+30Ω), Να	10 5μ prmal ±(0.11%+300	Ω A IΩ), Normal	100Ω 0.5μA ±(0.11%+1kΩ),	Normal ±(0.66%	1kΩ 100nA +10kΩ), Normal			
	Resistance	Temperature Coefficient	Test current Accuracy ±(0.15 × accuracy	1Ω 10μA ±(0.07%+30Ω), No ±(0.05%+10Ω), Enh specification)/°C (0°-	10 5μ 5μ 5μ 5μ 5μ 5μ 5μ 5μ 5μ 5μ	Ω A Ω), Normal 2), Enhanced ±(100Ω 0.5μA	Normal ±(0.66%	1kΩ 100nA			
	Resistance	Source I mode, Manual OHMS	Test current Accuracy ±(0.15 × accurac) Total uncertainty	1Ω 10µA ±(0.07%+30Ω), Νı ±(0.05%+10Ω), Enł specification)/°C (0°- = I source accuracy +	10 5μ prmal ±(0.11%+300 nanced ±(0.05%+1000	Ω A A Ω), Normal ± Ω), Enhanced ±(100Ω 0.5μA ±(0.11%+1kΩ),	Normal ±(0.66%	1kΩ 100nA +10kΩ), Normal			
	Resistance	Source I mode, Manual OHMS Source V mode, Manual OHMS 6-wire OHMS Mode	Test current Accuracy ±(0.15 × accuracy Total uncertainty Total uncertainty Available using a	1Ω 10µA ±(0.07%+30Ω), Nr ±(0.05%+10Ω), Enh specification)/°C (0°- = I source accuracy + = I source accuracy + trive ohms guard and trive ohms guard and	10/ 5μ prmal ±(0.11%+30C nanced ±(0.05%+1000 ~18°C & 28°~50°C) V measure accuracy (4-w	Ω A A Ω), Normal ± Ω), Enhanced ± ire remote sense) ire remote sense)	100Ω 0.5μA ±(0.11%+1kΩ), (0.05%+500Ω),	Normal ±(0.66% Enhanced ±(0.35%	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced			
	Resistance Maximum Range C	Source I mode, Manual OHMS Source V mode, Manual OHMS 6-wire OHMS Mode Guard Output Impedance	Test current Accuracy ±(0.15 × accuracy Total uncertainty Total uncertainty	1Ω 10µA ±(0.07%+30Ω), Nr ±(0.05%+10Ω), Enh specification)/°C (0°- = I source accuracy + = I source accuracy + trive ohms guard and trive ohms guard and	10: 5μ prmal ±(0.11%+30C tanced ±(0.05%+100Ω ~18°C & 28°~50°C) ✓ measure accuracy (4-w I measure accuracy (4-w	Ω A A Ω), Normal ± Ω), Enhanced ± ire remote sense) ire remote sense)	100Ω 0.5μA ±(0.11%+1kΩ), (0.05%+500Ω),	Normal ±(0.66% Enhanced ±(0.35%	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced			
	Maximum Range C	Source I mode, Manual OHMS Source V mode, Manual OHMS 6-wire OHMS Mode Guard Output Impedance	Test current Accuracy ±(0.15 × accuracy Total uncertainty Available using ai <0.1Ω in ohms m 75/second 40ms (fixed sour	1Ω 10µA ±(0.07%+30Ω), Nr specification)/°C (0°. = I source accuracy + = V source accuracy + titive ohms guard and ; ode ce) *6	100 544 547 547 547 547 547 547 547	Ω A Δ), Normal Δ), Enhanced ±(ire remote sense) ire remote sense) Output Current: 5	100Ω 0.5μA ±(0.11%+1kΩ), (0.05%+500Ω), 50mA (except 1)	Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is lo	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced	- Source IACC	 C+Meas.VACC	ssure Memory 10
	Maximum Range C Maximum Measur	Source I mode, Manual OHMS Source V mode, Manual OHMS 6-wire OHMS Mode Caurd Output Impedance change Rate Auto Range Time Speed	Test current Accuracy ±(0.15 x accuracy Total uncertainty Total uncertainty Available using a <0.10 in ohms m 75/second 40ms (fixed sourn NPLC / Trig Origin	1Ω ±(0.07%+30Q), N/ ±(0.05%+10Q), Enf specification)/°C (0° = I source accuracy + = V source accuracy + = V source accuracy + titve ohms guard and ; ode ce) *6 TO MEMORY	100 5µ prmal ±(0.11%+300) nanced ±(0.05%+1000) 18°C & 28°-50°C) 18°C & 28°-50°C) vmasure accuracy (4-w 1 measure accuracy (4-w I measure accuracy development 1 measure accuracy asure TO CPIB	Ω A (Ω), Normal (Ω), Enhanced ±(ire remote sense) ire remote sense) Output Current: <u>5</u> Sourc TO MEMORY	100Ω 0.5μA ±(0.11%+1kΩ), (0.05%+500Ω), 50mA (except 1/ ce-Measure *9 TO C	Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is lo Source PIB TO ME	1kΩ 100nA +10kΩ), Normal +SkΩ), Enhanced oad dependent e-Measure Pass/Fa MORY	Source IACC		
	Maximum Range C Maximum Measur Sequence Reading	Source I mode, Manual OHMS Source V mode, Manual OHMS &wire OHMS Mode Guard Output Impedance hange Rate Auto Range Time Speed Fast	Test current Accuracy ±(0.15 x accuracy Total uncertainty Total uncertainty Available using a <0.10. in ohms m 75/second 40ms (fixed sour NPLC / Trig Origin 0.01 / internal	1Ω ±(0.07%+300), N. ±(0.05%+10Ω), Enł specification)/*C (0° = I source accuracy + ± V source accuracy + ±tive ohms guard and ; ode Ee) *6 TO MEMORY 2081 (2030)	100 5µ pormal ±(0.11%+300 nanced ±(0.05%+1000 -18°C & 28°-50°C) V v measure accuracy (4-w guard sense. Max. Guard asure TO GPIB 1198 (1210) 1198 (1210)	Ω A Δ), Normal Ω), Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourco TO MEMORY 1551 (1515)	100Ω 0.5µA ±(0.11%+1kΩ), (0.05%+500Ω), 50mA (except 1) 50mA (except 1) ce-Measure *9 TO C 1000	Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is lo Sourc IPIB TO ME (900) 902 I	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent -Measure Pass/Fat MORY 900)	Source IACC ail test *8, *9 TO GPIB 309 (840)		Y TO GPIB 164 (162)
	Maximum Range (Maximum Measur Sequence Reading Rates +7 (rdg./second) for	Source I mode, Manual OHMS Source V mode, Manual OHMS Evvire OHMS Mode Guard Output Impedance Auto Range Time Speed Fast 488.2 Medium	Test current Accuracy ±(0.15 x accurac) Total uncertainty Total uncertainty Available using a <0.1Ω in ohms m	1Ω ±(0.07%+30Q), Nu ±(0.05%+10Q), Ent specification)/"C (0". = I source accuracy + = V source accuracy + = V source accuracy + titive ohms guard and ; ode code TO MEMORY 2081 (2030) 1239 (1200) 510 (433)	010 5µ prmal ±(0.11%+30C ianced ±(0.05%+100C 18°C & 28°-50°C Ymeasure accuracy (4-w Y measure accuracy (4-w yuard sense. Max. Guard TO GPIB 1198 (1210) 1198 (1210) 1079 (1050) 509 (433) 509 (433)	Ω A A A (0), Normal ±(ire remote sense) ire remote sense) Output Current: S Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405)	100Ω 0.5µA ±(0.11%+1kΩ), (0.05%+500Ω), 50mA (except 1) ce-Measure *9 TO C 1000 916 (470 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source Spin TO ME (900) 902 835) 830 410) 389	1kΩ 100nA +0kΩ), Normal +5kΩ), Enhanced bad dependent -Measure Pass/Fa MORY 900) 8 830) 7 343) 2	iil test *8, *9 TO GPIB 309 (840) 756 (780) 388 (343)		Y TO GPIB 164 (162) 162 (160) 132 (126)
	Maximum Range C Maximum Measur Sequence Reading Rates *7	Source I mode, Manual OHMS Source V mode, Manual OHMS Gwire OHMS Mode Cuard Output Impedance hange Rate e Auto Range Time Speed Fast 488.2 Medium 488.2	Test current Accuracy ±(0.15 × accuracy Total uncertainty Available using a <0.10 in ohms m 75/second 40ms (fixed sourd NPLC / Trig Origin 0.01 / internal 0.01 / internal 0.1 / external	1Ω ±(0.07%+300), N(±(0.05%+10Ω), Enf specification)/*C (0° = I source accuracy + ± V source accuracy + ± V source accuracy + ±tive ohms guard and ; ode TO MEMORY 2081 (2030) 1239 (1200) 1239 (1200) 510 (433) 438 (380)	100 5µ pormal ±(0.11%+300 nanced ±(0.05%+1000 18°C & 28°-50°C) V wasure accuracy (4-w Imeasure accuracy (4-w guard sense. Max. Guard sense. Max. TO C.PIB 1198 (1210) 1079 (1050) 509 (433) 438 (380) 438 (380)	Ω A (Ω), Normal (Ω), Enhanced ±! ire remote sense) Output Current: \$ Source TO MEMORY 1551 (1515) 1018 (990) 409 (360)	1000 0.5µA ±(0.11%+1k0), (0.05%+5000), 50mA (except 1/ 50mA (except 1/ 50mA (except 1/ 1000 1000 916 (4700 (470 (470 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is lo Sourc	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) § 830) 7 343) 2 333) 2	iil test *8, *9 TO CPIB 309 (840) 756 (780) 754 (333)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125)
YSTEM	Maximum Range (Maximum Measur Sequence Reading Rates +7 (rdg./second) for	Source I mode, Manual OHMS Source V mode, Manual OHMS Evvire OHMS Mode Guard Output Impedance Auto Range Time Speed Fast 488.2 Medium	Test current Accuracy ±(0.15 × accuracy) Total uncertainty Total uncertainty Available using at <0.1Ω in ohms mr	1Ω ±(0.07%+30Q), Nu ±(0.05%+10Q), Ent specification)/"C (0". = I source accuracy + = V source accuracy + = V source accuracy + titive ohms guard and ; ode code TO MEMORY 2081 (2030) 1239 (1200) 510 (433)	010 5µµ prmal ±(0.11%+30C ianced ±(0.05%+100C 18°C & 28°-50°C Ymessure accuracy (4-w Y measure accuracy (4-w yuard sense. Max. Guard TO GPIB 1198 (1210) 1079 (1050) 509 (433) 438 (380) 59 (43) 59 (48) 57 (48)	Ω A A A (0), Normal ±(ire remote sense) ire remote sense) Output Current: S Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405)	100Ω 0.5µA ±(0.11%+1kΩ), (0.05%+500Ω), 50mA (except 1) ce-Measure *9 TO C 1000 916 (470 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source Spin TO ME (900) 902 335) 830 345) 339 365) 374 48) 56 47) 56	1kΩ 100nA 100n, Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 333) 2	iil test *8. *9 TO CPIB 509 (840) 756 (780) 764 (333) 56 (47) 56 (47)		Y TO CPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38)
YSTEM PEED *5	Maximum Range Maximum Measur Sequence Reading Rates+7 (rdg./second) for 60Hz (50Hz) Single Reading	Source I mode, Manual OHMS Source V mode, Manual OHMS 6wire OHMS Mode Guard Output Impedance Auto Range Time Speed Fast 488.2 Medium 488.2 Normal	Test current Accuracy ±(0.15 × accuracy Total uncertainty Available using a <.0.10 in ohms m 75/second 40ms (fixed soun NPLC / Trig Origin 0.1 / internal 0.1 / external 1 / external 1 / external NPLC/ Trig	1Ω ±(0.07%+30Ω), Nu ±(0.05%+10Ω), Enf specification)/'C (0° = I source accuracy + = V source accuracy + = V source accuracy + titive ohms guard and p ode to MEMORY 2081 (2030) 1239 (1200) 510 (433) 438 (380) 59 (49)	100 5µ pormal ±(0.11%+300 hanced ±(0.05%+1000 18°C & 28°-50°C) Y measure accuracy (4-w measure accuracy (4-w guard sense. Max. Guard 1198 (210) 1079 (1050) 509 (433) 438 (380) 59 (49) 57 (48) Measure	Ω A A JQ, Normal JD, Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 58 (48)	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is lo	1kΩ 100nA 100n, Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 333) 2	iil test *8. *9 TO CPIB 509 (840) 756 (780) 764 (333) 56 (47) 56 (47)		Y TO CPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) 45 (38) 45 (38) 45 (38) 45 (38) 46 (38) 46 (38) 47 (38) 47 (38) 48
	Maximum Range (Maximum Measur Sequence Reading Rates+7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates	Source I mode, Manual OHMS Source V mode, Manual OHMS Evvire OHMS Mode Guard Output Impedance hange Rate e Auto Range Time Speed Fast 488.2 Medium 488.2 Normal 488.2 Speed Fast(488.2)	Test current Accuracy ±(0.15 × accuracy) Total uncertainty Total uncertainty Available using at <0.1Ω in ohms mr	1Ω ±(0.07%+30Ω), Nu ±(0.05%+10Ω), Enf specification)/'C (0° = I source accuracy + = V source accuracy + = V source accuracy + titive ohms guard and p ode to MEMORY 2081 (2030) 1239 (1200) 510 (433) 438 (380) 59 (49)	1010 10 17 18'C & 28'-50'C 10'2 & 28'-50'C 10'2 & 28'-50'C 10'2 & 21'2 & 21'2 & 21'2 10'2 & 21'2 & 21'2 10'2 & 10'2 & 10'2 10'2 & 10'2 10'2 & 10'2 & 10'2 10'2 & 10'2 & 10'2 10'2 & 10'2 & 10'2 10'2 & 10'2 & 10'2 10'2 & 10'2 & 10'2 10'2 & 10'2 & 10'2 10'2 & 10'2 & 10'2 10'2 & 10'2 & 10'2 10'2 & 10'2 10'2 & 10'2 & 10'2 10'2 10'2 & 10'2 10'2 & 10'2	Ω A A JQ, Normal JD, Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 58 (48)	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source Spin TO ME (900) 902 335) 830 340) 369 365) 374 48) 56 47) 56 Source-Measure *9 TO GPIB 79 (83) 83	1kΩ 100nA 100n, Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 333) 2	iil test *8. *9 TO CPIB 509 (840) 756 (780) 764 (333) 56 (47) 56 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) 45/Fail test *8, ≈9 PIB 3)
	Maximum Range C Maximum Measun Sequence Reading Rates +7 (rdg./second) for 60Hz (50Hz) Single Reading Operation Rates	Source I mode, Manual OHMS Source V mode, Manual OHMS Guite OHMS Mode Guard Output Impedance Auto Range Time Speed Fast 488.2 Medium 488.2 Normal 488.2 Speed	Test current Accuracy ±(0.15 × accuracy Total uncertainty Available using a <0.12 in ohms m 75/second 40ms (fixed sour NPLC / Trig Origin 0.01 / internal 0.1 / external 0.1 / external 1 / external NPLC/Trig Origin	1Ω ±(0.07%+30Ω), Nu ±(0.05%+10Ω), Enf specification)/'C (0° = I source accuracy + = V source accuracy + = V source accuracy + titive ohms guard and p ode to MEMORY 2081 (2030) 1239 (1200) 510 (433) 438 (380) 59 (49)	100 10 10 10 10 11 10 11	Ω A A JQ, Normal JD, Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 58 (48)	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is la	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 343) 2 347) 47	iil test *8. *9 TO CPIB 509 (840) 756 (780) 764 (333) 56 (47) 56 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) 44 (38) 55/Fail test *8. *9 PIB 3) 0)
	Maximum Range C Maximum Measur Sequence Reading Rates+7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component	Source I mode, Manual OHMS Source V mode, Manual OHMS Gurar V mode, Manual OHMS Guard Output Impedance hange Rate Auto Range Time Speed Fast 488.2 Normal 488.2 Speed Fast(488.2) Fast(488.2) Medium(488.2)	Test current Accuracy ±(0.15 × accuracy) Total uncertainty Total uncertainty Available using at <0.1Ω in ohms mr	1Ω ±(0.07%+30Ω), Nu ±(0.05%+10Ω), Enf specification)/'C (0° = I source accuracy + = V source accuracy + = V source accuracy + titive ohms guard and p ode to MEMORY 2081 (2030) 1239 (1200) 510 (433) 438 (380) 59 (49)	100 10 18℃ & 28′-50℃ 18℃ & 28′-50℃ 18℃ & 28′-50℃ 18℃ & 28′-50℃ 18℃ & 28′-50℃ 198 (1210) 1079 (1050) 1079 (1050) 509 (433) 438 (380) 59 (49) 5 (48) Measure TO GPIB 256 (256) 167 (166) 49 (42) Measure	Ω A A JQ, Normal JD, Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 58 (48)	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source Spin TO ME (900) 902 335) 830 410) 389 365) 374 48) 56 47) 56 Source-Measure *9 TO CP18 79 (83) 72 (70) 34 (31) Source Pass/Fail test	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 343) 2 347) 47	iil test *8, *9 TO GPIB 309 (840) 55 (780) 55 (47) 56 (47) 56 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) 44 (38) 164 (164) 174 (1
	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler	Source I mode, Manual OHMS Source V mode, Manual OHMS Fowire OHMS Mode Cuard Output Impedance Tange Rate Auto Range Time Speed Fast 488.2 Medium 488.2 Normal 488.2 Speed Fast(488.2) Medium(488.2) Normal(488.2) Speed Fast	Test current Accuracy ±(0.15 x accuracy Total uncertainty Available using a <0.10 in ohms m 75/second 40ms (fixed sourn NPLC / Trig 0.01 / internal 0.1 / external 1 / internal 1 / internal	1Ω 10µA ±(0.076×430), Nu ±(0.05%+100), Ent specification)/°C (0°) = I Source accuracy + = V source accuracy	100 100	Ω A A JQ, Normal JD, Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 58 (48)	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is le Source Image: Source Source (900) 902 410) 389 365) 374 95) Source Source-Measure So 70 GPIB 79 (83) 72 (70) 34 (31) Source Pass/Fail test TO GPIB 0.5 ms<(0.5 ms)	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 343) 2 347) 47	iil test *8, *9 TO GPIB 309 (840) 55 (780) 55 (47) 56 (47) 56 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 00 00 00 00 00 00 018 ss/Fail test *9, *11
	Maximum Range C Maximum Measur Sequence Reading Rates+7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Auto Range Time Speed Fast 488.2 Medium 488.2 Speed Fast(488.2) Medium(488.2) Normal 488.2 Speed Fast(488.2) Normal(488.2) Speed Fast Medium(488.2) Speed Fast Medium	Test current Accuracy ±(0.15 × accuracy) Total uncertainty Total uncertainty Available using at <0.10 in ohms m	1Ω ±(0.79%+30Q), NU ±(0.05%+10Ω), Enf specification)/*C (0°) = I source accuracy + = V source accuracy + =	100 10 18'C & 28'-50'C 18'C & 28'-50'C 18'C & 28'-50'C 18'C & 28'-50'C 10'2 (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 10'2 (10'2)	Ω A A JQ, Normal JD, Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 58 (48)	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source SPIB TO ME (900) 902 335) 334 335) 334 365) 374 48) 56 470 results 56 79 (83) 72 (70) 34 (31) Source Pass/Fail test TO CPIB 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms)	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 343) 2 347) 47	iil test *8, *9 TO GPIB 309 (840) 55 (780) 55 (47) 56 (47) 56 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 Ss/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler Time for 60Hz (50Hz) *8, *10	Source I mode, Manual OHMS Source V mode, Manual OHMS Gure V mode, Manual OHMS Guard Output Impedance Inange Rate Auto Range Time Speed Fast 488.2 Medium 488.2 Normal 488.2 Speed Fast(488.2) Medium(488.2) Normal(488.2) Speed Fast Medium Normal	Test current Accuracy ±(0.15 x accuracy Total uncertainty Available using a <.0.12 in ohms m 75/second 40ms (fixed sourn NPLC / Trig 0.01 / internal 0.1 / external 1.1 / internal 1.1 / external 1.1 / internal 1.1 / internal	1Ω ±(0.07%+300), N. ±(0.05%+100), Enf specification)/"C (0") = I source accuracy + = V source accuracy + = V source accuracy + titive ohms guard and ; ode TO MEMORY 2081 (2030) 1239 (1200) 1239 (1200) 510 (433) 438 (380) 59 (49) 57 (48) 	100 100	Ω A A JQ, Normal JD, Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 58 (48)	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is le Source Image: Source Source (900) 902 410) 389 365) 374 95) Source Source-Measure So 70 GPIB 79 (83) 72 (70) 34 (31) Source Pass/Fail test TO GPIB 0.5 ms<(0.5 ms)	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 343) 2 347) 47	iil test *8, *9 TO GPIB 309 (840) 55 (780) 55 (47) 56 (47) 56 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 Ss/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg./second) for 60Hz (50Hz) Single Reading Operation Rates (rdg./second) for 60Hz (50Hz) Component Interface Handler Time for 60Hz (50Hz) *8, *10 Load Impedance Differential Mode'	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Tange Rate Auto Range Time Speed Fast 488.2 Medium 488.2 Speed Fast(488.2) Medium(488.2) Normal 488.2 Speed Fast(488.2) Speed Fast Medium Normal Voltage	Test current Accuracy ±(0.15 × accuracy Total uncertainty Available using a <0.10 in ohms m 75/second 40ms (fixed sourd NPLC / Trig Origin 0.01 / internal 0.1 / external 1 / external 1 / external 1 / external 1 / external 1 / external 1 / internal 1 / internal 250VPK	1Ω ±(0.07%+300), N. ±(0.05%+100), Enf specification)/"C (0") = I source accuracy + = V source accuracy + = V source accuracy + titive ohms guard and ; ode TO MEMORY 2081 (2030) 1239 (1200) 1239 (1200) 510 (433) 438 (380) 59 (49) 57 (48) 	100 10 18'C & 28'-50'C 18'C & 28'-50'C 18'C & 28'-50'C 18'C & 28'-50'C 10'2 (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 10'2 (10'2)	Ω A A JQ, Normal JD, Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 58 (48)	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source SPIB TO ME (900) 902 335) 334 335) 334 365) 374 48) 56 470 results 56 79 (83) 72 (70) 34 (31) Source Pass/Fail test TO CPIB 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms)	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 343) 2 347) 47	iil test *8, *9 TO GPIB 309 (840) 55 (780) 55 (47) 56 (47) 56 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 Ss/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler Time for 60Hz (50Hz) *8, *10 Load Impedance Differential Mode Common Mode Is	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Inange Rate Auto Range Time Speed Fast 488.2 Normal 488.2 Speed Fast(488.2) Medium(488.2) Normal(488.2) Speed Fast Medium(488.2) Speed Fast Medium Normal Normal	Test current Accuracy ±(0.15 × accuracy) Total uncertainty Available using a <0.1Ω in ohms m	1Ω ±(0.7%+30Q), Nu ±(0.25%+10Q), Enf specification)/°C (0°) = I Source accuracy + = V	100 10 18'C & 28'-50'C 18'C & 28'-50'C 18'C & 28'-50'C 18'C & 28'-50'C 10'2 (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 10'2 (10'2)	Ω A A JQ, Normal JD, Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 58 (48)	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source SPIB TO ME (900) 902 335) 334 335) 334 365) 374 48) 56 470 results 56 79 (83) 72 (70) 34 (31) Source Pass/Fail test TO CPIB 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms)	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 343) 2 347) 47	iil test *8, *9 TO GPIB 309 (840) 55 (780) 55 (47) 56 (47) 56 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 0) 55/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (S0Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (S0Hz) Component Interface Handler Time for 60Hz (S0Hz) *8, *10 Load Impedance Differential Model Common Mode V Common Mode V Common Mode V	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Tange Rate Auto Range Time Speed Fast 488.2 Medium 488.2 Normal 488.2 Speed Fast(488.2) Medium(488.2) Speed Fast Medium(488.2) Speed Fast Medium Normal Voltage olation	Test current Accuracy ±(0.15 × accuracy) Total uncertainty Available using a <0.1Ω in ohms m	1Ω ±(0.07%+300), N. ±(0.05%+100), Enf specification)/"C (0") = I source accuracy + = V source accuracy + = V source accuracy + titive ohms guard and ; ode TO MEMORY 2081 (2030) 1239 (1200) 1239 (1200) 510 (433) 438 (380) 59 (49) 57 (48) 	100 10 18'C & 28'-50'C 18'C & 28'-50'C 18'C & 28'-50'C 18'C & 28'-50'C 10'2 (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 10'2 (10'2)	Ω A A JQ, Normal JD, Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 58 (48)	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source Spinor TO ME (900) 902 385) 830 365) 374 48) 56 470 rcs-Measure *9 TO GPIB 79 (83) 72 (70) 34 (31) Source Pass/Fail test TO GPIB 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms)	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 343) 2 347) 47	iil test *8, *9 TO GPIB 309 (840) 55 (780) 55 (47) 56 (47) 56 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 0) 55/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler Time for 60Hz (50Hz) *8, *10 Load Impedance Differential Mode ¹ Common Mode Is Over Range Max. Voltage Drop Max. Sense Lead R	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Tange Rate Auto Range Time Speed Fast 488.2 Medium 488.2 Normal 488.2 Speed Fast(488.2) Medium(488.2) Normal(488.2) Speed Fast Medium Normal Voltage oltage oltage oltage sistance	Test current Accuracy ±(0.15 × accuracy) Total uncertainty Available using a <0.1Ω in ohms m	1Ω ±(0.7%+30Q), Nu ±(0.25%+10Q), Enf specification)/°C (0°) = I Source accuracy + = V	100 10 18'C & 28'-50'C 18'C & 28'-50'C 18'C & 28'-50'C 18'C & 28'-50'C 10'2 (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 10'2 (10'2)	Ω A A JQ, Normal JD, Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 58 (48)	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source Spinor TO ME (900) 902 385) 830 365) 374 48) 56 470 rcs-Measure *9 TO GPIB 79 (83) 72 (70) 34 (31) Source Pass/Fail test TO GPIB 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms)	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 343) 2 347) 47	iil test *8, *9 TO GPIB 309 (840) 55 (780) 55 (47) 56 (47) 56 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 Ss/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interfrace Handler Time for 60Hz (50Hz) *8, *10 Load Impedance Differential Mode Common Mode Is Over Range Max. Voltage Drop Max. Sense lead R Sense Input Impec Guard Offset Volta	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Inarge Rate Auto Range Time Speed Fast 488.2 Normal 488.2 Speed Fast(488.2) Medium(488.2) Speed Fast Medium(488.2) Speed Fast Medium(488.2) Speed Fast Medium(488.2) Speed Fast Medium Normal Normal	Test current Accuracy ±(0.15 × accuracy) Total uncertainty Total uncertainty Available using a -0.10 in ohms mr 40ms (fixed sourd) VPC/ Trig 0.01 / internal 0.1 / internal 0.1 / internal 0.1 / internal 1.1 / external 0.01 / internal 0.1 / internal 1.1 / external 0.1 / internal 0.1 / internal <	1Ω 10µA ±(0.07%+30Q), Nu ±(0.05%+10Q), Enf specification)/'C (0') = I source accuracy + = V source accuracy	100 5µµ pormal ±(0.11%+30C ianced ±(0.05%+100C -18°C & 28°-50°C) Wreasure accuracy (4-w I measure accuracy (4-w I measure accuracy (4-w asure 1198 (1210) 1079 (1050) 509 (433) 438 (380) 59 (49) 57 (48) Measure TO GPIB 256 (256) 167 (166) 49 (42) Measure TO GPIB 2.55 ms (2.9 ms) 7.33 ms (20.9 ms)	Ω A A D), Normal ire remote sense) Output Current: 5 Output Current: 5 TO MEMORY 1551 (1515) 1018 (48) 57 (48) 0 0 0	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source Spinor TO ME (900) 902 385) 830 365) 374 48) 56 470 rcs-Measure *9 TO GPIB 79 (83) 72 (70) 34 (31) Source Pass/Fail test TO GPIB 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms)	1kΩ 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 343) 2 347) 47	iil test *8, *9 TO GPIB 309 (840) 55 (780) 55 (47) 56 (47) 56 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 Ss/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
PEED *5	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler Zommon Mode IS Common Mode IS Over Range Max. Voltage Drop Max. Sense lead R Sense Input Impec Guard Offset Volta	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Thange Rate Auto Range Time Speed Fast 488.2 Medium 488.2 Normal 488.2 Speed Fast(488.2) Medium(488.2) Normal(488.2) Speed Fast Medium Normal Voltage olation sistance ance ge	Test current Accuracy ±(0.15 × accuracy) Total uncertainty Available using a <0.1Ω in ohms m	1Ω 10µA ±(0.07%+30Q), Nu ±(0.05%+10Q), Enf specification)/'C (0') = I source accuracy + = V source accuracy	100 10 18'C & 28'-50'C 18'C & 28'-50'C 18'C & 28'-50'C 18'C & 28'-50'C 10'2 (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 1 measure accuracy (4-w 10'2 (10'2)	Ω A A D), Normal ire remote sense) Output Current: 5 Output Current: 5 TO MEMORY 1551 (1515) 1018 (48) 57 (48) 0 0 0	1000 0.5µA ±(0.1196+1k0), (0.055%+5000), 50mA (except 1) 50mA (except 1) 50mA (except 1) 1000 916 (409 (409 (58 (Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source Spinor TO ME (900) 902 385) 830 365) 374 48) 56 470 rcs-Measure *9 TO GPIB 79 (83) 72 (70) 34 (31) Source Pass/Fail test TO GPIB 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms)	1kΩ 100nA 100n, Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 900) 8 330) 2 343) 2 343) 2 347) 47	iil test *8, *9 TO GPIB 309 (840) 55 (780) 55 (47) 56 (47) 56 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 0) 55/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interfrace Handler Time for 60Hz (50Hz) *8, *10 Load Impedance Differential Mode Common Mode Is Over Range Max. Voltage Drop Max. Sense lead R Sense Input Impec Guard Offset Volta	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Thange Rate Auto Range Time Speed Fast 488.2 Medium 488.2 Normal 488.2 Speed Fast(488.2) Medium(488.2) Normal(488.2) Speed Fast Medium Normal Voltage olation sistance ance ge	Test current Accuracy ±(0.15 × accuracy) Total uncertainty Total uncertainty Available using a <0.10 in ohms mr	1Ω 10µA ±(0.07%+30Ω), Nu ±(0.05%+10Ω), Enf specification)/'C (0') = I source accuracy + = V source accuracy	100 5μ parmal ±(0.11%+30C taraced ±(0.05%+100C -18°C & 28°-50°C) Ymeasure accuracy (4-w measure accuracy (4-w ymeasure accuracy (4-w TO CPIB 1198 (1210) 1079 (1050) 509 (433) 438 (380) 59 (449) 57 (48) Measure TO CPIB 256 (256) 167 (166) 49 (42) Measure TO CPIB 2.55 ms (2.9 ms) 7.33 ms (20.9 ms) 7.53 ms (20.9 ms) 5.55 ms (2.9 ms) ction), Stair (linear and k	Ω A A A A A A A A A A A A A A A A A A A D), Enhanced ±(ire remote sense) Output Current: 5 Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 409 (360) 57 (48) Sourc A A A A A A A A A A A A A A A A A A A B A B A B B B B B B B B B B B B <td>1000 0.5µA ±(0.17%+1kg), (0.05%+5000), (0.05%+500), (0.05%+5000), (0.05%</td> <td>Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source SPIB TO ME (900) 902 385) 383 385) 374 48) 56. 77 561 79 (83) 72 (70) 34 (31) Source Pass/Fail test TO CPIB 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms)</td> <td>1kΩ 100nA 100nA, +10kΩ), Normal +5kΩ), Enhanced bad dependent -Measure Pass/F6 MORY 2000 8300 3333 3333 47) 47)</td> <td>iil test *8, *9 TO CPIB 309 (840) 755 (780) 1888 (343) 74 (333) 55 (47) 55 (47) 55 (47) 55 (47) 55 (47)</td> <td></td> <td>Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 0) 55/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)</td>	1000 0.5µA ±(0.17%+1kg), (0.05%+5000), (0.05%+500), (0.05%+5000), (0.05%	Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is log Source SPIB TO ME (900) 902 385) 383 385) 374 48) 56. 77 561 79 (83) 72 (70) 34 (31) Source Pass/Fail test TO CPIB 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms)	1kΩ 100nA 100nA, +10kΩ), Normal +5kΩ), Enhanced bad dependent -Measure Pass/F6 MORY 2000 8300 3333 3333 47) 47)	iil test *8, *9 TO CPIB 309 (840) 755 (780) 1888 (343) 74 (333) 55 (47) 55 (47) 55 (47) 55 (47) 55 (47)		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 0) 55/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
PEED *5	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler Time for 60Hz (50Hz) *8, *10 Load Impedance Differential Mode ¹ Common Mode Is Over Range Max. Voltage Drop Max. Sense lead R Sense Input Impec Guard Offset Volta Source Output Mo Source Memory Lii Memory Buffer Programmability	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Thange Rate Auto Range Time Speed Fast 488.2 Medium 488.2 Normal 488.2 Speed Fast(488.2) Medium(488.2) Normal(488.2) Speed Fast Medium Normal Voltage olation sistance ance ge des st	Test current Accuracy ±(0.15 × accuracy Total uncertainty Available using a <0.1Ω in ohms m	1Ω 10µA ±(0.076×30Q), Nu ±(0.05%+10Ω), Enf specification//°C (0°) = I Source accuracy + = V source accuracy	100 10 10 18'C & 28'-50'C) 18'C & 28'-50'C) 18'C & 28'-50'C) 18'C & 28'-50'C) 19'C & 28'-50'C) 10'21'01'10'21'01'20'10'10'10'10'10'10'10'10'10'10'10'10'10	Ω A AD, Normal D), Enhanced ±j), Enhanced <td>1000 0.5µA ±(0.178+tlk), (0.05%+5000), (0.05%+500), (0.05%+5000), (0.05%</td> <td>Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is la </td> <td>1kΩ 100nA 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/FE MORY 900) 830) 7333) 333) 47) 47) 900 900 900 901 902 47) 903 9047) 900</td> <td>iil test *8, *9 TO GPIB 809 (840) 55 (780) 55 (47) 56 (47) 56</td> <td></td> <td>Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 Ss/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)</td>	1000 0.5µA ±(0.178+tlk), (0.05%+5000), (0.05%+500), (0.05%+5000), (0.05%	Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is la	1kΩ 100nA 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/FE MORY 900) 830) 7333) 333) 47) 47) 900 900 900 901 902 47) 903 9047) 900	iil test *8, *9 TO GPIB 809 (840) 55 (780) 55 (47) 56		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 Ss/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
PEED *5	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler Time for 60Hz (50Hz) +8, +10 Load Impedance Differential Mode Common Mode Is Over Range Max. Voltage Drop Max. Sense lead R Sense Input Impec Guard Offset Volta Source Output Mo Source Output Mo Source Output Mo Source Memory Li Source Memory Li Source The Source Source Memory Li Source Source Source Memory Li Source Memory Li Source Memory Li Source Memory Li Source Memory Li Digital I/O Connec	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Thange Rate Auto Range Time Speed Fast 488.2 Medium 488.2 Normal 488.2 Speed Fast(488.2) Medium(488.2) Normal(488.2) Speed Fast Medium Normal Voltage olation sistance ance ge des st	Test current Accuracy ±(0.15 × accuracy) Total uncertainty Total uncertainty Available using a <0.01 in ohms mr	1Ω 10µA ±(0.07%+30Ω), Nu ±(0.05%+10Ω), Enf specification)/'C (0°- I Source accuracy + = V source accuracy +	100 5μ parmal ±(0.11%+30C taraced ±(0.05%+100C -18°C & 28°-50°C) 700 reasure accuracy (4-w measure accuracy (4-w measure accuracy (4-w 198 (1210) 1079 (1050) 509 (433) 438 (380) 59 (443) 57 (48) Measure TO GPIB 256 (256) 167 (166) 49 (42) Measure TO GPIB 2.55 ms (2.9 ms) 7.33 ms (20.9 ms) 7.33 ms (20.9 ms) 513 (49) ction), Stair (linear and k bint buffers). Includes sel able power-up states plus ction), Stair grup states plus	Q A A), Normal ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 409 (360) 57 (48) 57 (48) 0 0 0 0 0 0 0 0 0 0 0 0 0	1000 0.5µA ±(0.17%+1kg), (0.05%+5000), (0.05%+500), (0.05%+5000), (0.05%	Normal ±(0.66% Enhanced ±(0.35% Arange). Accuracy is la Source PIB TO ME (900) 902.1 335) 330.1 410) 389 365) 374.4 48) 56.1 70 GORIE 79 (83) 72 (70) 34 (31) Source Pass/Fail test 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) US ms) 0.5 ms (0.5 ms) US ms) e stamp. Lithium battet 4 TTL/Relay Drive out	1kΩ 100nA 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/FE MORY 900) 830) 7333) 333) 47) 47) 900 900 900 901 902 47) 903 9047) 900	iil test *8, *9 TO GPIB 809 (840) 55 (780) 55 (47) 56		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 Ss/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
PEED *5	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler Common Mode IS Over Range Max. Voltage Drop Max. Sense lead R Sense Input Impec Guard Offset Volta Source Output Md Source Output Md Source Memory Li Memory Buffer Programmability Disguing Jones Content Remote Interface	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Thange Rate Auto Range Time Speed Fast 488.2 Normal 488.2 Normal 488.2 Speed Fast(488.2) Medium(488.2) Speed Fast Medium(488.2) Speed Fast Medium Normal Voltage blage	Test current Accuracy ±(0.15 × accuracy Total uncertainty Available using a <0.1Ω in ohms m	1Ω ±(0.79%-30Q), Nu ±(0.25%+10Q), Enf specification//°C (0°) = I Source accuracy + = V source accuracy + =	100 10 10 18'C & 28'-50'C) 18'C & 28'-50'C) 18'C & 28'-50'C) 18'C & 28'-50'C) 19'C & 28'-50'C) 19'S (210) 10'Z (1050) 10'Z (1050	Ω A), Normal)), Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 470 (405) 470 (405) 57 (48) 57 (48)	1000 0.5µA ±(0.17%+1kg), (0.05%+5000), (0.05%+500), (0.05%+5000), (0.05%	Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is la	1kΩ 100nA 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent bad dependent c-Measure Pass/FE MORY 900) \$230) 333) 333) 47) 47) 47) y 47) y	iil test *8, *9 TO GPIB 809 (840) 55 (780) 55 (47) 56		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 Ss/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
PEED *5	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler Time for 60Hz (50Hz) +8, +10 Load Impedance Differential Mode Common Mode Is Over Range Max. Voltage Drop Max. Sense lead R Sense Input Impec Guard Offset Volta Source Output Mo Source Output Mo Source Output Mo Source Memory Li Source Memory Li Source The Source Source Memory Li Source Source Source Memory Li Source Memory Li Source Memory Li Source Memory Li Source Memory Li Digital I/O Connec	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Cuard Output Impedance Tast Fast 488.2 Medium 488.2 Speed Fast(488.2) Kormal 488.2 Speed Fast(488.2) Speed Fast Medium Normal Voltage olation	Test current Accuracy ±(0.15 × accuracy) Total uncertainty Total uncertainty Available using a <0.01 in ohms mr	1Ω 10µA ±(0.07%+30Ω), Nu ±(0.05%+10Ω), Enf specification)/'C (0°. = I source accuracy + = V source accuracy	100 10 10 18'C & 28'-50'C) 18'C & 28'-50'C) 18'C & 28'-50'C) 18'C & 28'-50'C) 19'C & 28'-50'C) 19'S (1210) 10'79 (1210) 10'79 (1210) 10'79 (1050) 509 (433) 438 (380) 57 (48) Measure TO CPIB 256 (256) 167 (166) 157 (166) 155 ms (20 9 ms) 7.53 ms (20 9 ms) 7.53 ms (20 9 ms) ction), Stair (linear and le able power-up states plu 10 able power	Ω A), Normal)), Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 470 (405) 470 (405) 57 (48) 57 (48)	1000 0.5µA ±(0.17%+1kg), (0.05%+5000), (0.05%+500), (0.05%+5000), (0.05%	Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is la	1kΩ 100nA 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent bad dependent c-Measure Pass/FE MORY 900) \$230) 333) 333) 47) 47) 47) y 47) y	iil test *8, *9 TO GPIB 809 (840) 55 (780) 55 (47) 56		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 Ss/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
PEED *5	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler Common Mode IS Over Range Max. Voltage Drop Max. Sense lead R Sense Input Impec Guard Offset Volta Source Output Md Source Output Md Sou	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Cuard Output Impedance Cuard Output Impedance Fast Fast 488.2 Normal 488.2 Normal 488.2 Speed Fast(488.2) Medium(488.2) Speed Fast Medium(488.2) Speed Fast Medium Normal Voltage base st tor ment ent ent	Test current Accuracy ±(0.15 × accuracy Total uncertainty Available using a <0.1Ω in ohms m	1Ω 10µA ±(0.07%+30Ω), Nu ±(0.05%+10Ω), Enf specification)/'C (0°. = I source accuracy + = V source accuracy	100 10 10 18'C & 28'-50'C) 18'C & 28'-50'C) 18'C & 28'-50'C) 18'C & 28'-50'C) 19'C & 28'-50'C) 19'S (1210) 10'79 (1210) 10'79 (1210) 10'79 (1050) 509 (433) 438 (380) 57 (48) Measure TO CPIB 256 (256) 167 (166) 157 (166) 155 ms (20 9 ms) 7.53 ms (20 9 ms) 7.53 ms (20 9 ms) ction), Stair (linear and le able power-up states plu 10 able power	Ω A), Normal)), Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 470 (405) 470 (405) 57 (48) 57 (48)	1000 0.5µA ±(0.17%+1kg), (0.05%+5000), (0.05%+500), (0.05%+5000), (0.05%	Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is la	1kΩ 100nA 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent bad dependent c-Measure Pass/FE MORY 900) \$230) 333) 333) 47) 47) 47) y 47) y	iil test *8, *9 TO GPIB 809 (840) 55 (780) 55 (47) 56		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 Ss/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
PEED *5	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler Time for 60Hz (50Hz) +8, +10 Load Impedance Differential Mode Common Mode Is Over Range Max. Voltage Drop Max. Sense lead R Sense Input Impec Guard Offset Volta Source Output Mo Source Output Mo Source Output Mo Source Output Mo Source Interface Insulation Operation Environm	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Cuard Output Impedance Cuard Output Impedance Cuard Output Impedance Fast 488.2 Speed Fast 488.2 Speed Fast(488.2) Normal 488.2 Speed Fast(488.2) Speed Fast Medium Normal Voltage olation	Test current Accuracy ± (0.15 × accuracy) Total uncertainty Total uncertainty Available using a <0.01 in ohms m	1Ω 10µA ±(0.07%+30Ω), Nu ±(0.05%+10Ω), Enf specification)/'C (0°. = I source accuracy + = V source accuracy	100 Sµµ prmal ±(0.11%+30C nanced ±(0.05%+100C 18°C & 28°-50°C) 18°C & 28°-50°C) 18°C & 28°-50°C) 18°C 198°C & 28°-50°C) 198°C 198°C & 28°-50°C) 198°C 1998 12100 1079 1079 1079 1079 509 433 438<(380)	Ω A), Normal)), Enhanced ±(ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 470 (405) 470 (405) 57 (48) 57 (48)	1000 0.5µA ±(0.17%+1kg), (0.05%+5000), (0.05%+500), (0.05%+5000), (0.05%	Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is la	1kΩ 100nA 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent bad dependent c-Measure Pass/FE MORY 900) \$230) 333) 333) 47) 47) 47) y 47) y	iil test *8, *9 TO GPIB 809 (840) 55 (780) 55 (47) 56		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 00 Ss/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
YSTEM ENERAL	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler Time for 60Hz (50Hz) +8, +10 Load Impedance Differential Mode Common Mode V Common Mode V Source Output Mo Source Output Mo Source Output Mo Source Consumption Differention Environ Storage Environme Input Power Power Consumptic Dimensions & We	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Cuard Output Impedance Cuard Output Impedance Speed Fast 488.2 Normal 488.2 Speed Fast Medium(488.2) Speed fast Medium Normal Voltage blation fint for fint fint fint fint fint fint fint fint	Test current Accuracy ± (0.15 × accuracy) Total uncertainty Total uncertainty Available using a <0.01 in ohms m	1Ω ±(0.79%+30Q), Nu ±(0.05%+10Q), Enf specification)/°C (0°. = I source accuracy + = V	100 10 10 11 10 11	Ω A) (D), Normal (D), Enhanced ±() (ire remote sense) (ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (990) 470 (405) 470 (405) 470 (405) 57 (48) 57 (48)	1000 0.5µA ±(0.17%+1kg), (0.05%+5000), (0.05%+500), (0.05%+5000), (0.05%	Normal ±(0.66% Enhanced ±(0.35% A range). Accuracy is la	TkΩ 100nA 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent c-Measure Pass/Fa MORY 2 900) 830) 2 333) 2 47) 47) y </td <td>iil test ≈8, ≈9 TO GPIB 309 (840) 55 (780) 88 (343) 55 (47) 55 (47) 56 (47) 5</td> <td></td> <td>Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 0) 55/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)</td>	iil test ≈8, ≈9 TO GPIB 309 (840) 55 (780) 88 (343) 55 (47) 55 (47) 56 (47) 5		Y TO GPIB 164 (162) 162 (160) 132 (126) 131 (125) 44 (38) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 0) 55/Fail test *9, *11 PIB 5.3 ms) -1.1 ms)
EED *5	Maximum Range C Maximum Measur Sequence Reading Rates +7 (rdg,/second) for 60Hz (50Hz) Single Reading Operation Rates (rdg,/second) for 60Hz (50Hz) Component Interface Handler Time for 60Hz (50Hz) +8, +10 Load Impedance Differential Model Common Mode Is Common Mode Is Source Cutput Mo Source Cutput Mo Digital I/O Connet Insulation Operation Environ Storage Environme Input Power Power Consumptit	Source I mode, Manual OHMS Source V mode, Manual OHMS Source V mode, Manual OHMS Guard Output Impedance Cuard Output Impedance Cuard Output Impedance Speed Fast 488.2 Normal 488.2 Speed Fast Medium(488.2) Speed fast Medium Normal Voltage blation fint for fint fint fint fint fint fint fint fint	Test current Accuracy ± (0.15 × accuracy) Total uncertainty Total uncertainty Available using a <0.01 in ohms m	1Ω ±(0.79%+30Q), Nu ±(0.05%+10Q), Enf specification)/°C (0°. = I source accuracy + = V	100 50 parmal ±(0.11%+30C nanced ±(0.05%+100C 18°C & 28°-50°C) 18°C & 28°-50°C) measure accuracy (4-w I measure accuracy (4-w TO CPIB 1198 (1210) 1079 (1050) 509 (433) 438 (380) 59 (49) 57 (48) Measure TO CPIB 126 (256) 167 (166) 44 (42) Measure TO GPIB 1.04 rms (1.08 ms) 2.55 ms (2.9 ms) 7.53 ms (20.9 ms) 7.53 ms (20.9 ms) ction), Stair (linear and le bint buffers), Includes sel able power-up states plus, r, 3 category bits. ; +5V@ (DC 500V) ; Chassis and temperature: 0 ~ 40°C Rr 80% ox. 4.8kg ACCEESSORI	Ω A A D), Normal D), Enhanced ±j ire remote sense) ire remote sense) Output Current: 5 Sourc TO MEMORY 1551 (1515) 1018 (90) 470 (405) 409 (360) 57 (48) D	1000 0.5µA ±(0.11%+1kg), (0.05%+5000), (0.05%+500), (0.05%+5000), (0.05%	Normal ±(0.66% Enhanced ±(0.35% Enhanced ±(0.35% A range). Accuracy is la Source (900) 902.1 335) 330.1 410) 389.9 365) 374.4 48) 56.1 70 GPIB 70 GPIB 70 GPIB 79 (83) 72 (70) 34 (31) Source Pass/Fail test 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) 0.5 ms (0.5 ms) US ms (0.5 ms) 0.5 ms (0.5 m	1kΩ 100nA 100nA 100nA +10kΩ), Normal +5kΩ), Enhanced bad dependent bad dependent c-Measure Pass/FE MORY 900) 2830) 7333) 333) 47) 47) 900 900 900 900 900 900 901 902 903 903 900	iil test *8, *9 Source IACC iiil test *8, *9 TO GPIB 309 (840) 55 (780) 388 (343) 374 (333) 55 (47) 56		Y TO CPIB 164 (162) 162 (160) 132 (126) 44 (38) ss/Fail test *8, *9 PIB 3) 0) 0) 0, ss/Fail test *8, *9 PIB 25.0 ms) 55.0 ms) 55.0 ms)

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